

Atty. Docket No. 10191/4246	Serial No. 10/534,603		
Applicant(s) HARTER et al.			
Filing Date	Group		

To Be Assigned

## INFORMATION DISCLOSURE STATEMENT BY APPLICANTS PTO FORM 1449

## **U. S. PATENT DOCUMENTS**

May 11, 2005

EXAMINER'S INITIALS	PATENT NUMBER	PATENT DATE	NAME	CLASS	SUBCLASS	FILING DATE

## FOREIGN PATENT DOCUMENTS

EXAMINER'S INITIALS	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB-CLASS	TRANSI	ATION
						YES	NO

## OTHER DOCUMENTS

EXAMINER'S INITIALS	AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.
/SR/	M. Abramovici et al., "Digital Systems Testing And Testable Design", IEEE Press 1990. *
/SR/	R. N. Williams "A Painless Guide to CRC Error Detection Algorithms, Version 3, 8/19/1993, Rocksoft^tm Pty Ltd. Australia. *

<sup>\*</sup>Described in the Specification.

EXAMINER	/Samir Rizk/ (02/20/2008)	DATE CONSIDERED			
EXAMINER: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.					